

# BSS84

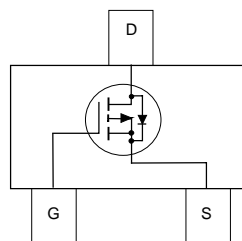
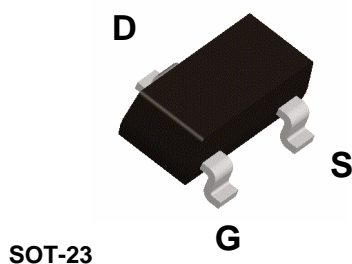
## P-Channel Enhancement Mode Field Effect Transistor

### General Description

These P-Channel enhancement mode field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. They can be used, with a minimum of effort, in most applications requiring up to 0.13A DC and can deliver current up to 0.52A. This product is particularly suited to low voltage applications requiring a low current high side switch.

### Features

- -0.13A, -50V.  $R_{DS(ON)} = 10\Omega @ V_{GS} = -5V$
- Voltage controlled p-channel small signal switch
- High density cell design for low  $R_{DS(ON)}$
- High saturation current



### Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DSS}$	Drain-Source Voltage	-50	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$I_D$	Drain Current – Continuous (Note 1)	-0.13	A
	– Pulsed	-0.52	
$P_D$	Maximum Power Dissipation (Note 1)	0.36	W
	Derate Above $25^\circ\text{C}$	2.9	mW/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purposes, 1/16" from Case for 10 Seconds	300	

### Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	350	$^\circ\text{C}/\text{W}$
-----------------	--	-----	---------------------------

### Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
SP	BSS84	7"	8mm	3000 units

**Electrical Characteristics** $T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
--------	-----------	-----------------	-----	-----	-----	-------

**Off Characteristics**

$BV_{DSS}$	Drain–Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = -250\ \mu\text{A}$	-50			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = -250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		-48		mV/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -50\text{ V}, V_{GS} = 0\text{ V}$			-15	$\mu\text{A}$
		$V_{DS} = -50\text{ V}, V_{GS} = 0\text{ V}, T_J = 125^\circ\text{C}$			-60	$\mu\text{A}$
$I_{GSS}$	Gate–Body Leakage.	$V_{GS} = \pm 20\text{ V}, V_{DS} = 0\text{ V}$			$\pm 10$	nA

**On Characteristics (Note 2)**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -1\text{ mA}$	-0.8	-1.7	-2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = -1\text{ mA}$ , Referenced to $25^\circ\text{C}$		3		mV/ $^\circ\text{C}$
$R_{DS(on)}$	Static Drain–Source On–Resistance	$V_{GS} = -5\text{ V}, I_D = -0.10\text{ A}$		1.2	10	$\Omega$
		$V_{GS} = -5\text{ V}, I_D = -0.10\text{ A}, T_J = 125^\circ\text{C}$		1.9	17	
$I_{D(on)}$	On–State Drain Current	$V_{GS} = -5\text{ V}, V_{DS} = -10\text{ V}$	-0.6			A
$g_{FS}$	Forward Transconductance	$V_{DS} = -25\text{ V}, I_D = -0.10\text{ A}$	0.05	0.6		S

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = -25\text{ V}, V_{GS} = 0\text{ V}, f = 1.0\text{ MHz}$		73		pF
$C_{oss}$	Output Capacitance			10		pF
$C_{rss}$	Reverse Transfer Capacitance			5		pF
$R_G$	Gate Resistance	$V_{GS} = -15\text{ mV}, f = 1.0\text{ MHz}$		9		$\Omega$

**Switching Characteristics (Note 2)**

$t_{d(on)}$	Turn–On Delay Time	$V_{DD} = -30\text{ V}, I_D = -0.27\text{ A}, V_{GS} = -10\text{ V}, R_{GEN} = 6\ \Omega$		2.5	5	ns
$t_r$	Turn–On Rise Time			6.3	13	ns
$t_{d(off)}$	Turn–Off Delay Time			10	20	ns
$t_f$	Turn–Off Fall Time			4.8	9.6	ns
$Q_g$	Total Gate Charge	$V_{DS} = -25\text{ V}, I_D = -0.10\text{ A}, V_{GS} = -5\text{ V}$		0.9	1.3	nC
$Q_{gs}$	Gate–Source Charge			0.2		nC
$Q_{gd}$	Gate–Drain Charge			0.3		nC

**Drain–Source Diode Characteristics and Maximum Ratings**

$I_S$	Maximum Continuous Drain–Source Diode Forward Current				-0.13	A
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = -0.26\text{ A}$ (Note 2)		-0.8	-1.2	V
$t_{rr}$	Diode Reverse Recovery Time	$I_F = -0.10\text{ A}$		10		nS
$Q_{rr}$	Diode Reverse Recovery Charge	$d_{IF}/d_t = 100\text{ A}/\mu\text{s}$ (Note 2)		3		nC

**Notes:**

- $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



- $350^\circ\text{C}/\text{W}$  when mounted on a minimum pad..

Scale 1 : 1 on letter size paper

- Pulse Test: Pulse Width  $\leq 300\ \mu\text{s}$ , Duty Cycle  $\leq 2.0\%$

Typical Characteristics

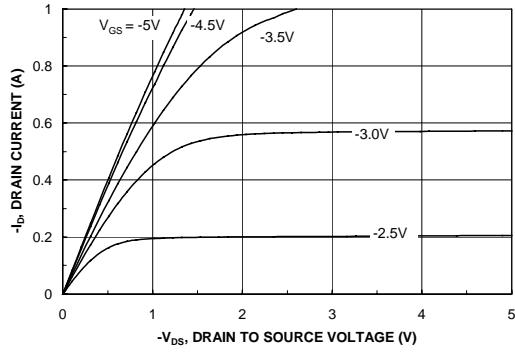


Figure 1. On-Region Characteristics.

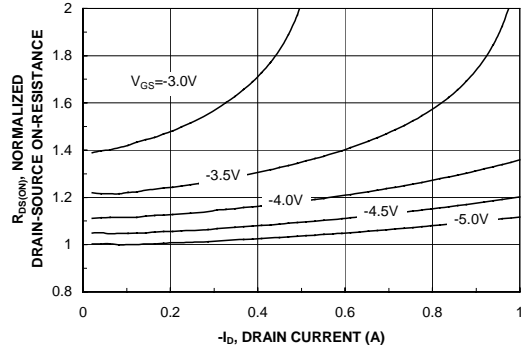


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

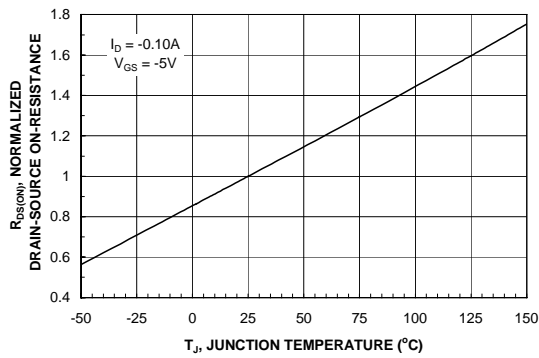


Figure 3. On-Resistance Variation with Temperature.

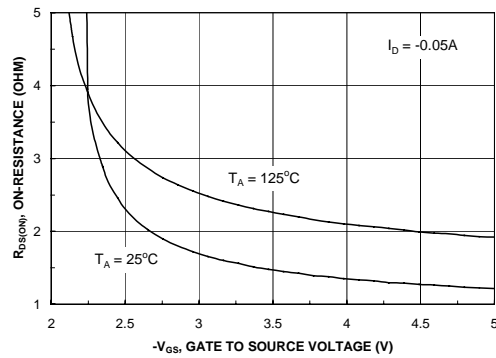


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

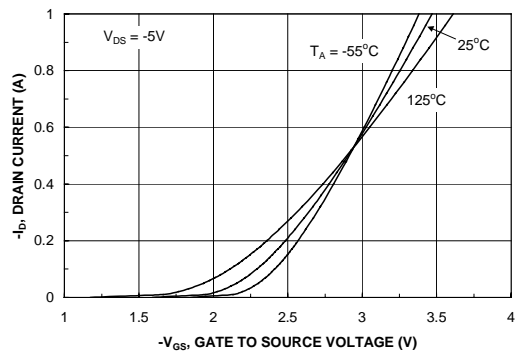


Figure 5. Transfer Characteristics.

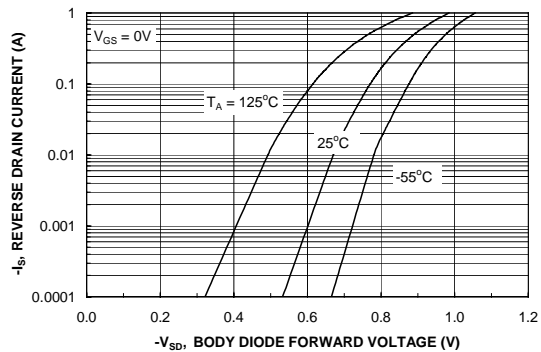


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

### Typical Characteristics

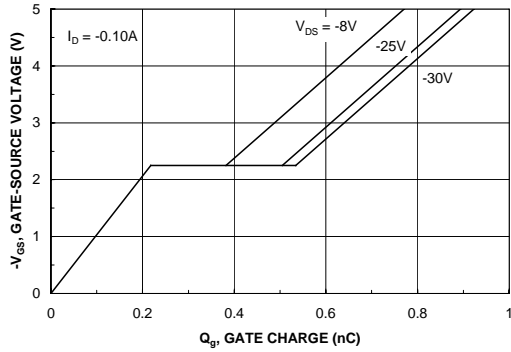


Figure 7. Gate Charge Characteristics.

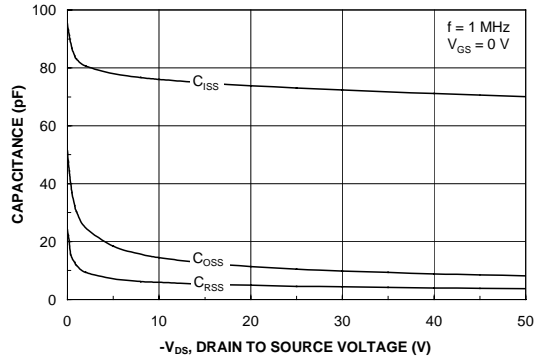


Figure 8. Capacitance Characteristics.

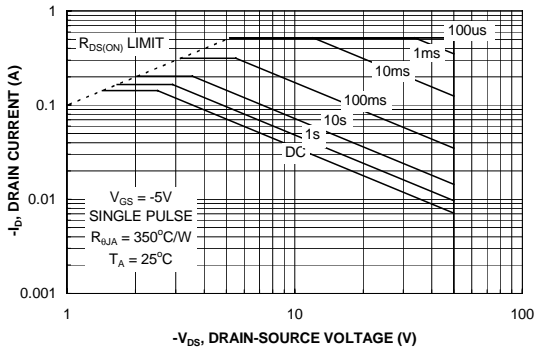


Figure 9. Maximum Safe Operating Area.

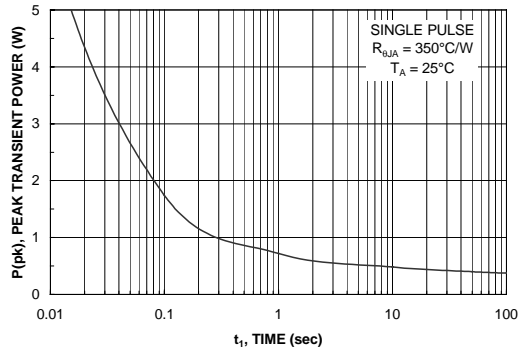


Figure 10. Single Pulse Maximum Power Dissipation.

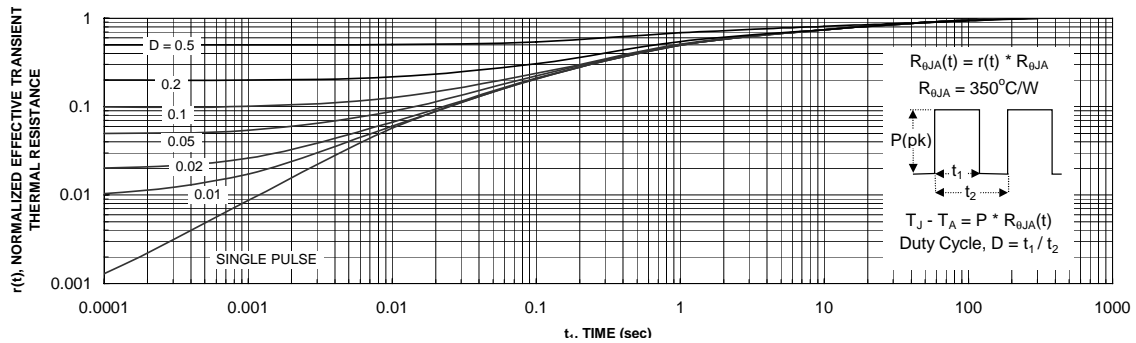


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1a. Transient thermal response will change depending on the circuit board design.